

Search Notes

Application/Control No.

10/594,282

Examiner

Sin J. Lee

Applicant(s)/Patent under
Reexamination

ISHII ET AL.

Art Unit

1795

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EIC Structure searches for claims 18, 35 and 38.	11/3/2008	SJL
East text search	11/3/2008	SJL